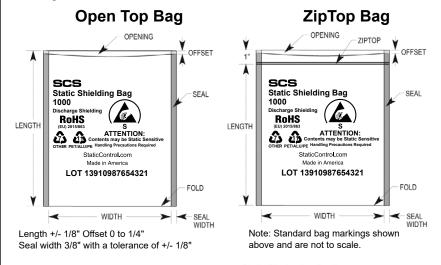
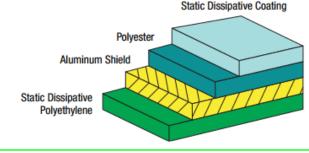
Static Shielding Bag 1000 Series



This transparent metal-in static shielding bag is designed to provide a static safe environment for ESD sensitive electronic devices. Bags are printed with an ESD protective symbol and a lot code for traceability. Open top (1000 Series) and ZipTop (3000 Series) styles are available. The bags are heat sealable.

SCS Static Shielding Bags 1000 Series are manufactured from a polyester, metal, polyethylene laminate. The polyester dielectric in concert with the metal layer provides discharge shielding. The exterior being static dissipative allows electrostatic charges to be removed when grounded.





RoHS, REACH and Conflict Minerals, Statement See the Desco Industries RoHS, REACH, and Conflict Minerals Statement:

See the SCS Limited Warranty:

Meets ANSI/ESD S20.20, Packaging standard ANSI/ESD S541, and Static Control Bag ANSI/ESD S11.4 Level 3

Physical	Typical Value	Testing Method
Tensile Strength	4600 PSI, 32 MPa	ASTM D882
Puncture Resistance	12 lbs, 53 N	MIL-STD-3010C Method 2065
Seal Strength	11 lbs, 48 N	ASTM D882
Thickness	2.8 mils, 0.071 mm +/-10%	MIL-STD-3010C Method 1003
Marking Adhesion	Pass	IPC-TM-650 2.4.1
Transparency	40%	Tobias
Electrical	Typical Value	Testing Method
ESD Shielding	<10 nJ	ANSI/ESD STM11.31
Surface Resistance - Interior	$1 \times 10^4 \text{ to} < 1 \times 10^{11} \text{ ohms}$	ANSI/ESD STM11.11
Surface Resistance - Exterior	< 1 x 10 ¹¹ ohms	ANSI/ESD STM11.11
Static Decay	< 2 seconds	ETS 406D
Cleanliness	Typical Value	Testing Method
Silicone	Not Detected	FTIR
Heat Sealing Conditions	Typical Value	
Temperature	300°F – 375°F, 149°C – 190°C	
Time	0.5 - 3.5 seconds	
Pressure	30 – 70 PSI. 206 – 482 KPa	

Bag is free of amines, silicones and heavy metals.

This product is intended for commercial use only. This product is not on the Qualified Product Listing under the Defense Standardization Program.



Specifications and procedures subject to change without notice.

1000 SERIES STATIC SHIELDING BAG

DRAWING NUMBER 1000 Series April 2019

SCS